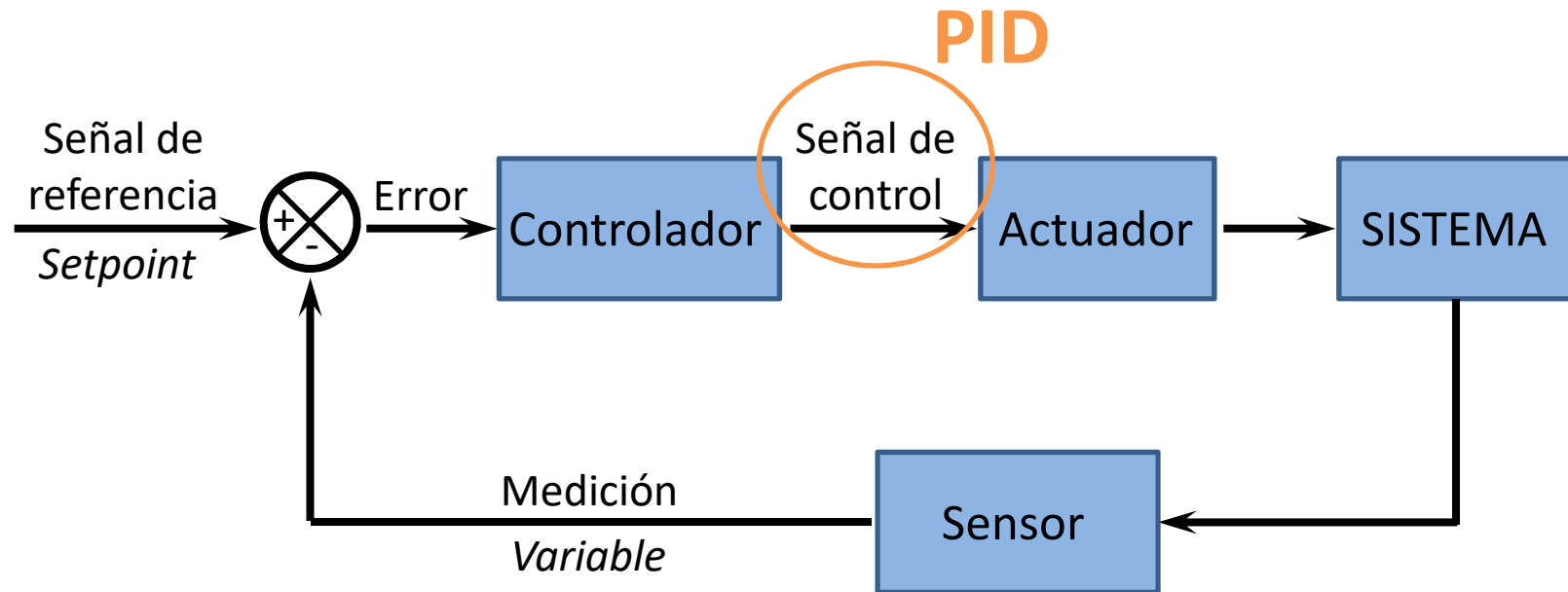


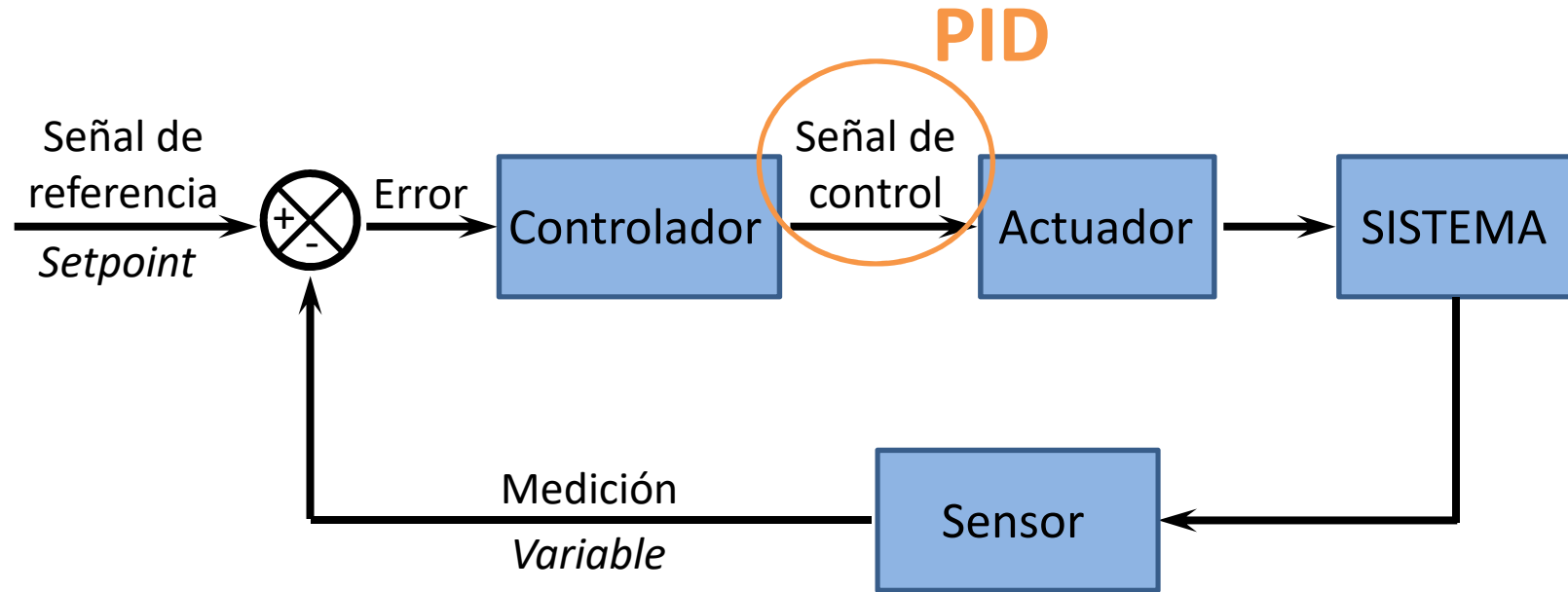
Lazo de realimentación PID (en AFM)

Laboratorio 5 – Abril 2017

Lazo de Control



Lazo de Control



Error

$$e(t) = \textit{setpoint} - \textit{variable}(t)$$

Señal de control PID

$$u(t) = K_P \cdot e(t) + K_I \cdot \overset{\text{integral}}{\int_0^t e(\tau) d\tau} + K_D \cdot \frac{de(t)}{dt}$$

proporcional

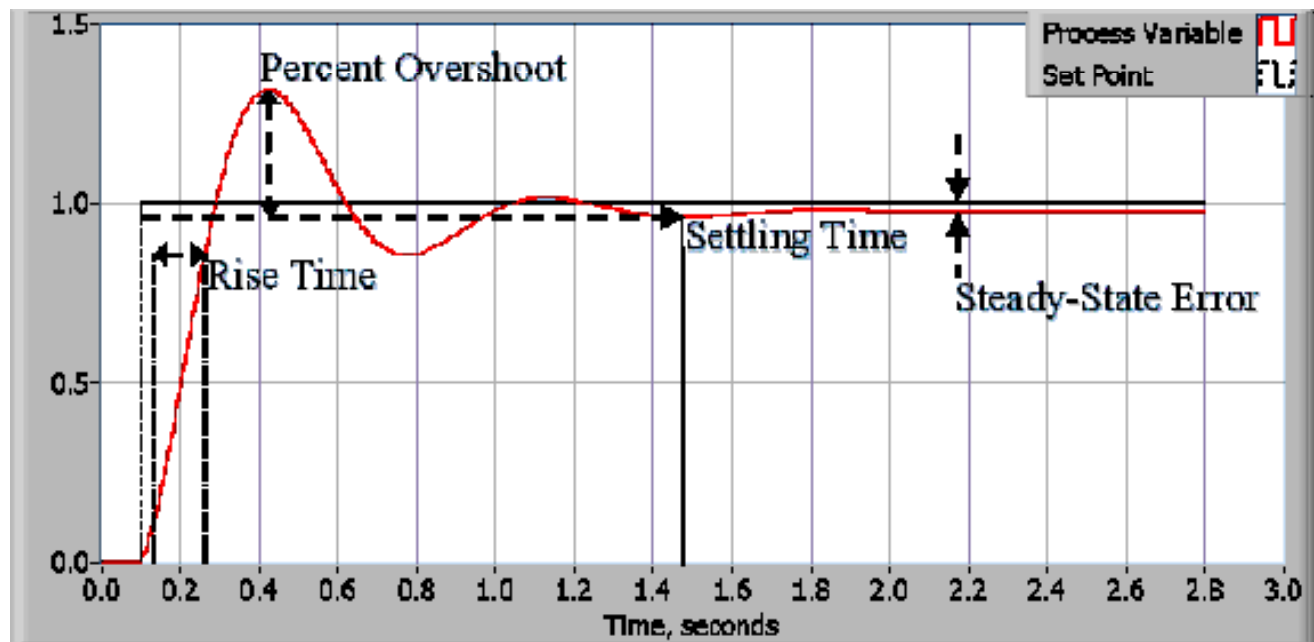
derivativo

Señal de control PID

$$u(t) = K_P \cdot e(t) + K_I \cdot \int_0^t e(\tau) d\tau + K_D \cdot \frac{de(t)}{dt}$$

K_P, K_I, K_D ?

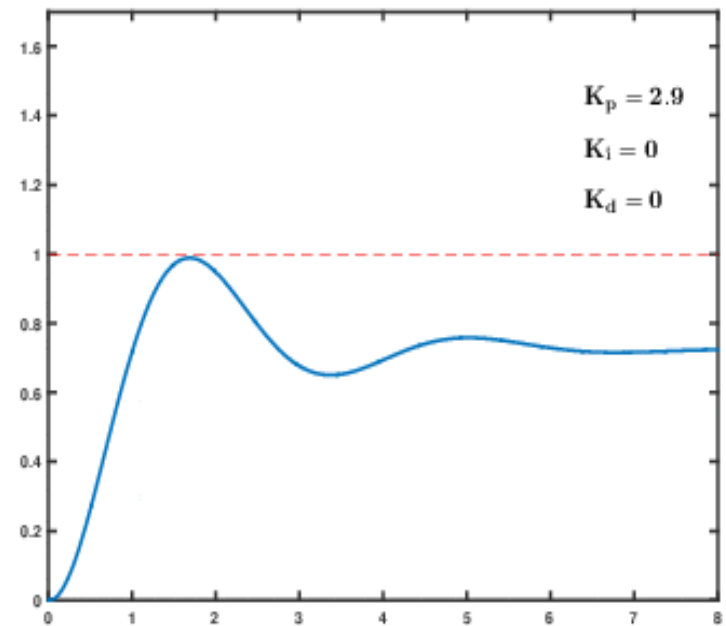
Las ganancias influyen en la performance del sistema:
cómo responde el sistema ante un cambio de Setpoint



Señal de control PID

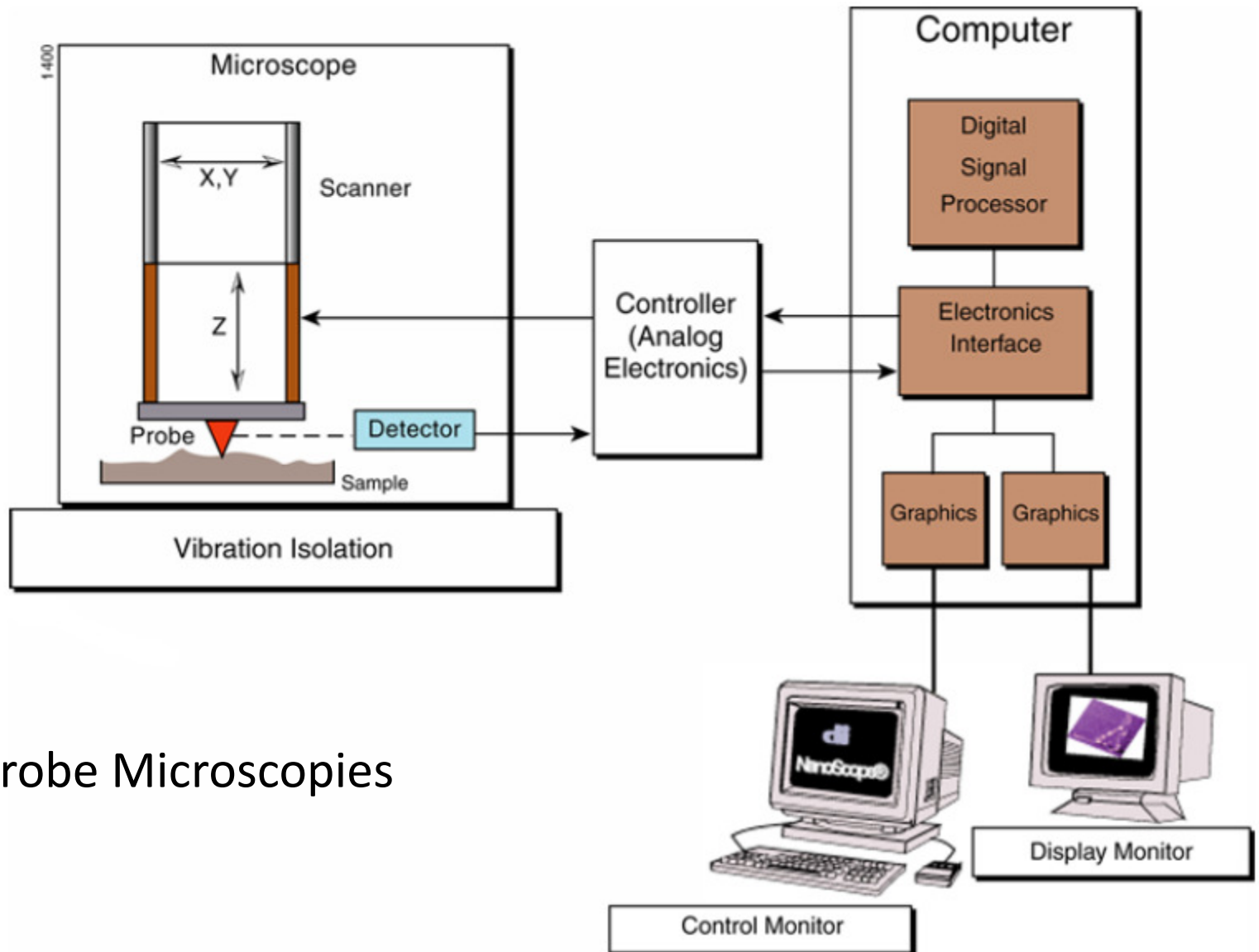
$$u(t) = K_P \cdot e(t) + K_I \cdot \int_0^t e(\tau) d\tau + K_D \cdot \frac{de(t)}{dt}$$

- **Proporcional:** Directamente proporcional al error. Aumentar K_P mejora la velocidad de respuesta. Empiezan a verse oscilaciones.
- **Integral:** suma el error en el tiempo. Mayor K_I mejora el steady state error (*Windup*)
- **Derivativo:** Proporcional a la tasa de cambio. Mejora la respuesta. Muy sensible al ruido.



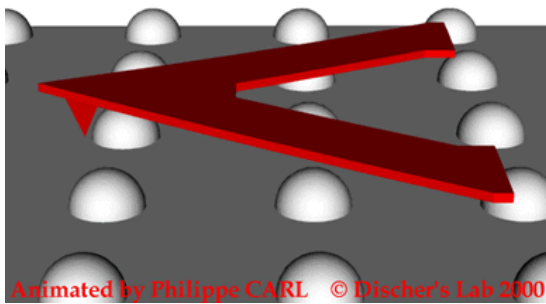
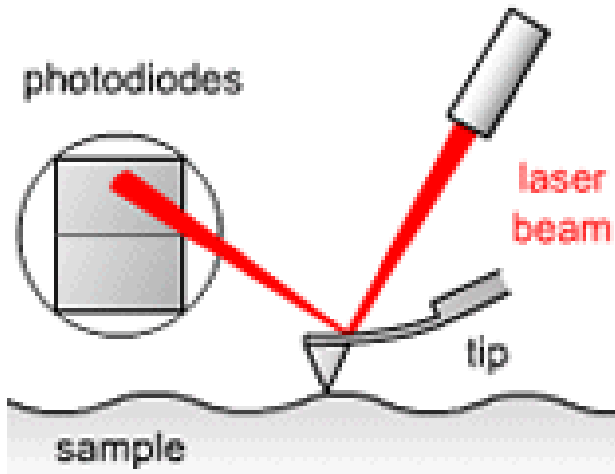
en.wikipedia.org/wiki/PID_controller#/media/File:PID_Compensation_Animated.gif

SPM



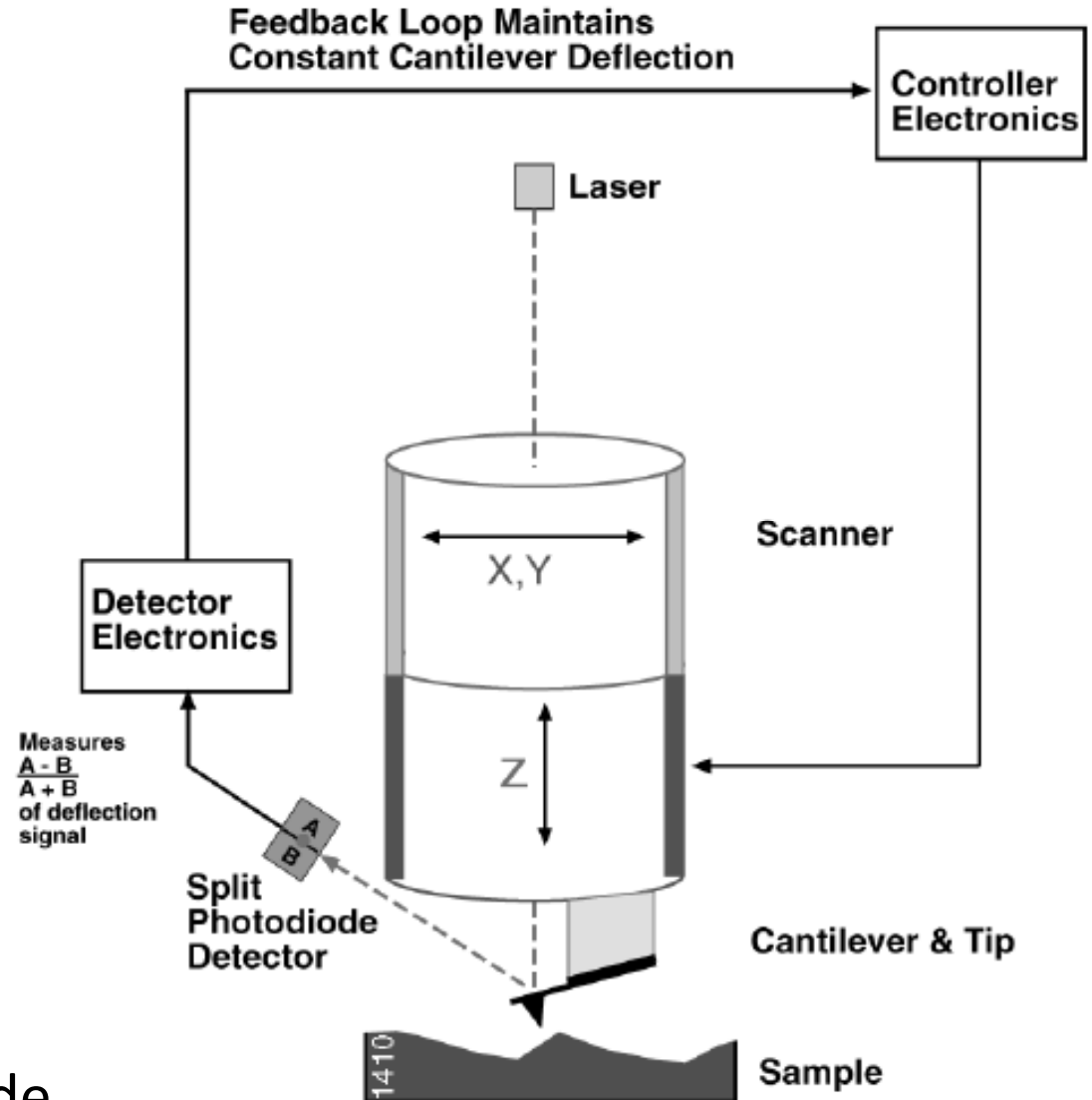
Scanning Probe Microscopies

AFM

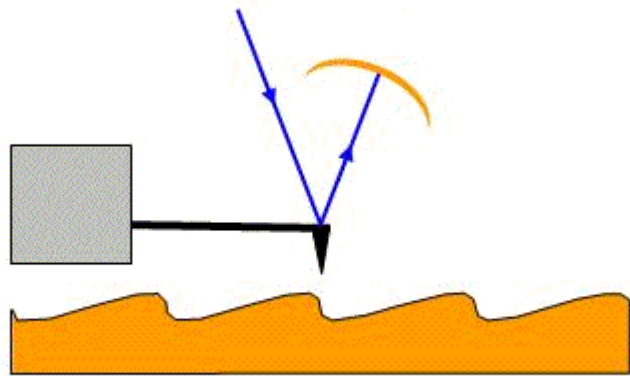


<http://perso.univ-lemans.fr/~bardeau/IMMM-PEC/afm>

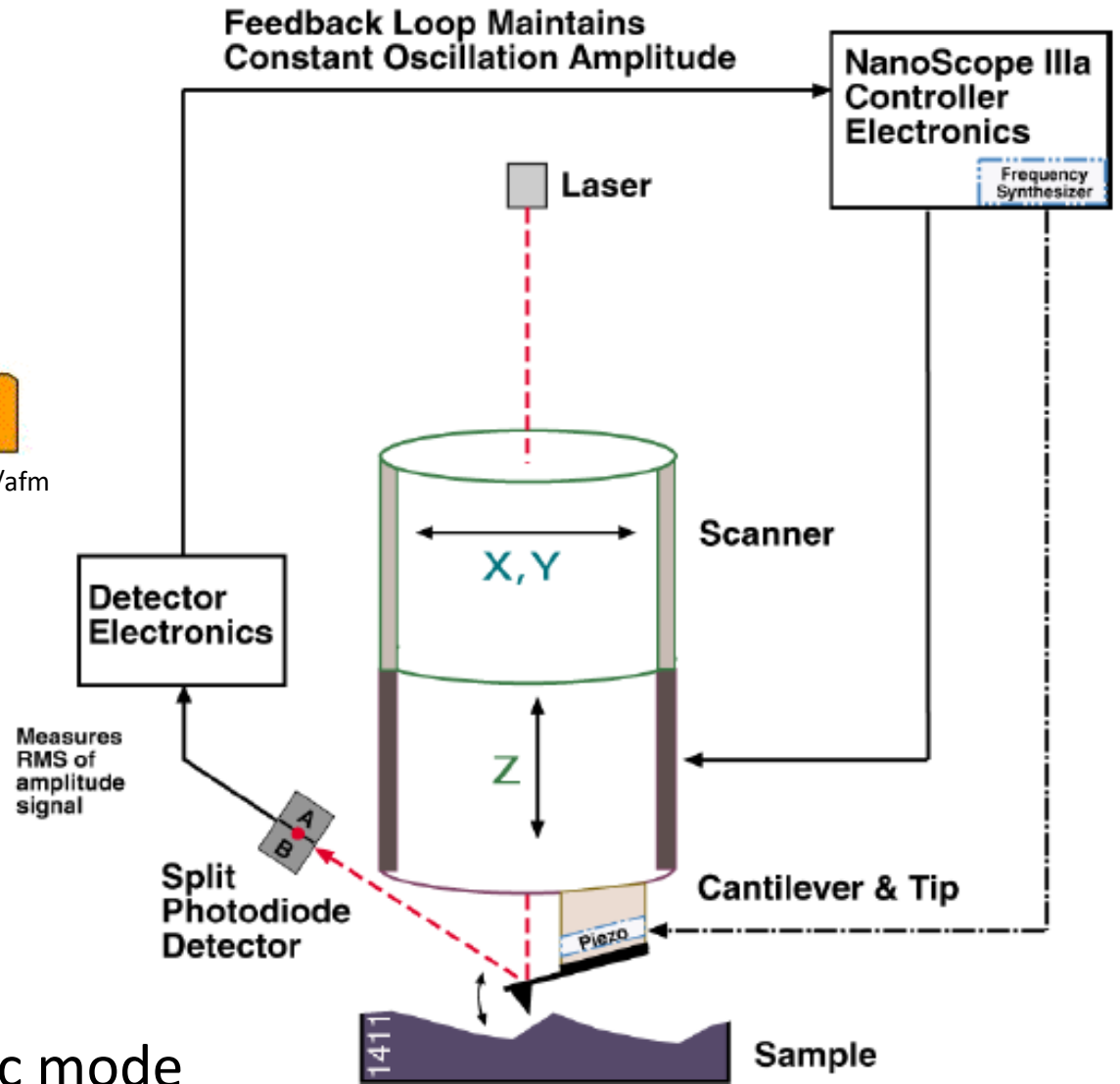
Contact mode / Static mode



AFM



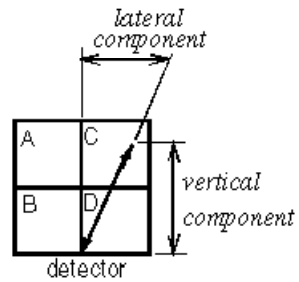
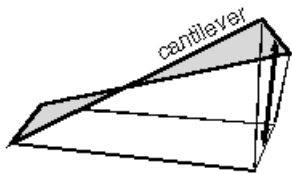
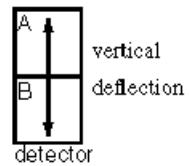
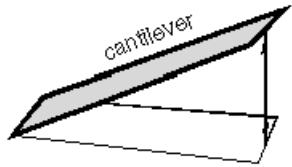
<http://perso.univ-lemans.fr/~bardeau/IMMM-PEC/afm>



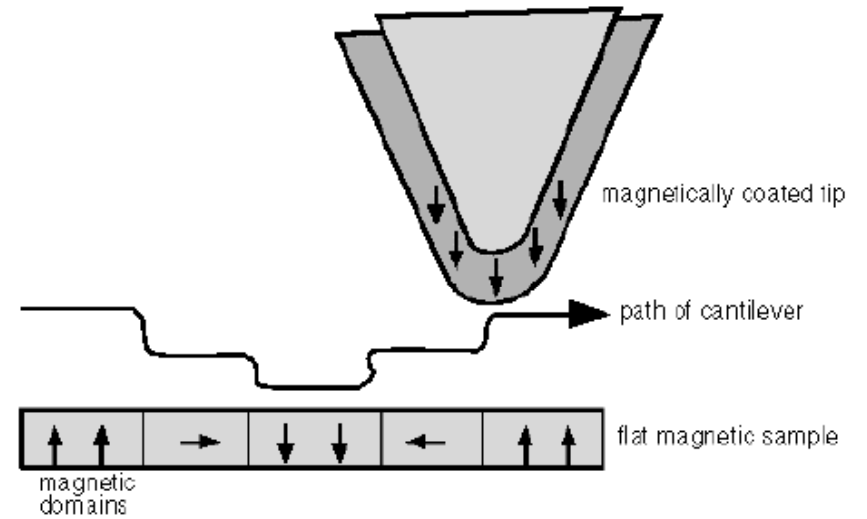
Tapping mode / Dynamic mode

AFM

Otros modos de imaging

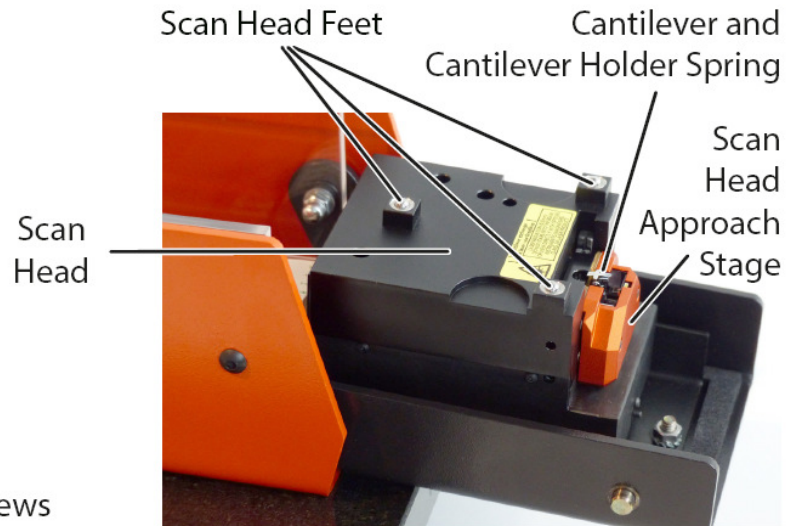
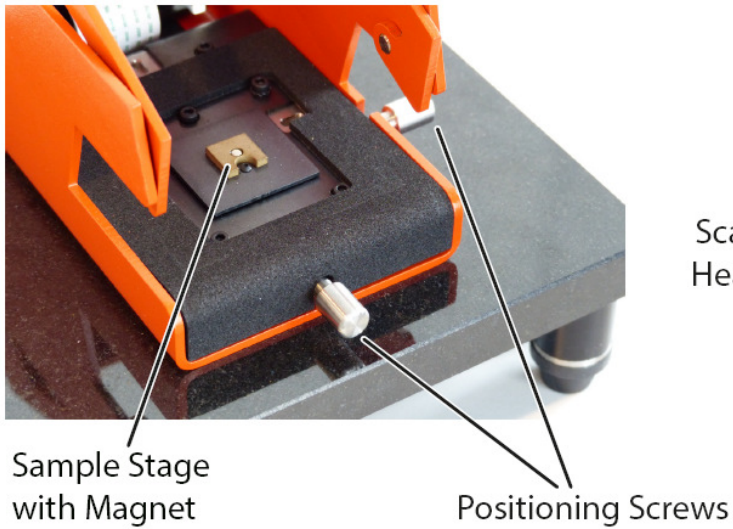
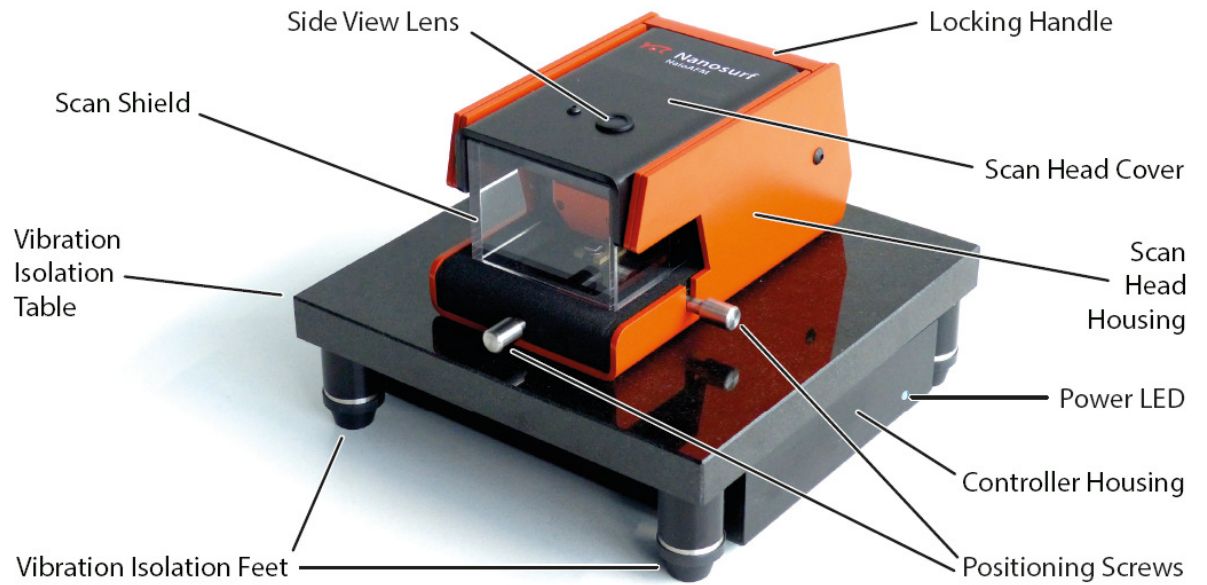


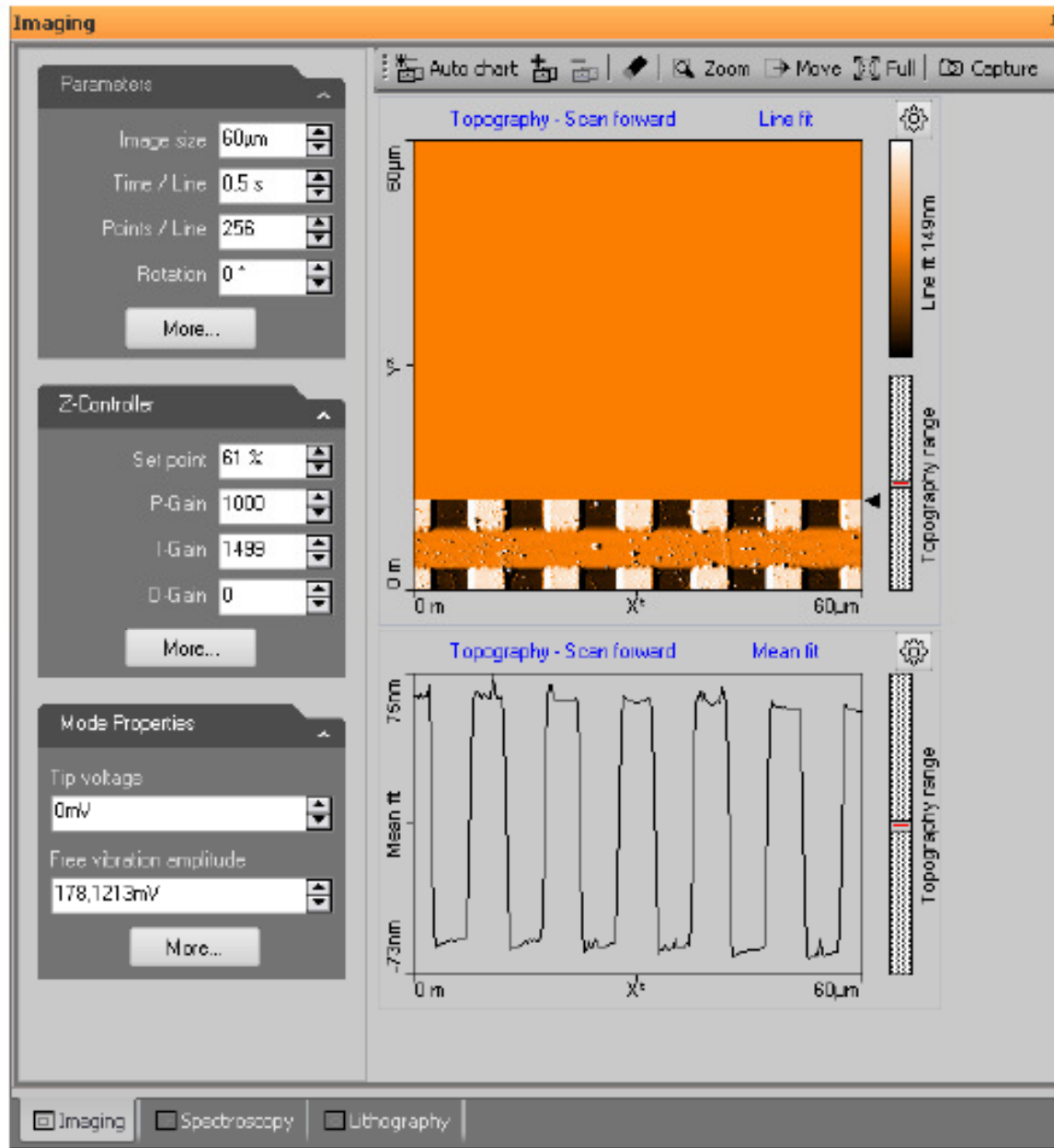
Lateral force
(Friction images)



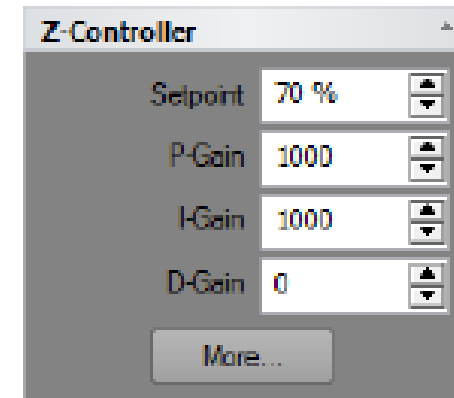
Magnetic Force Microscopy

AFM





Z-controller section



Set point (%)

P - Gain

I - Gain

D - Gain

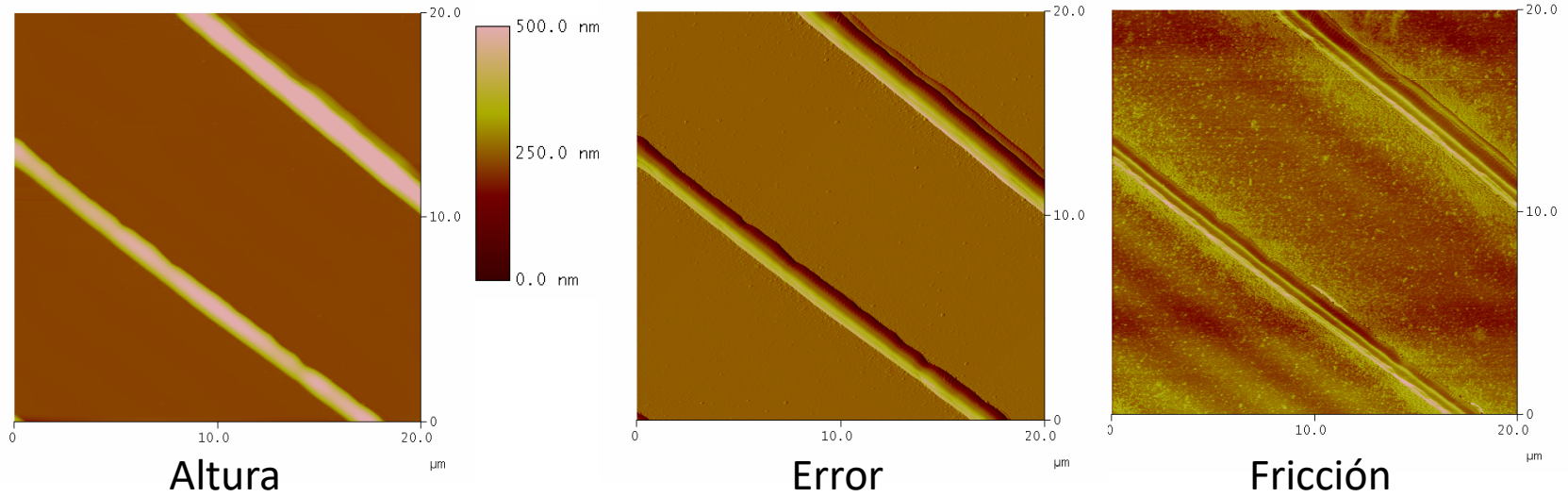
•El Setpoint y las ganancias se ajustan optimizando la imagen.

•La vista de perfiles permite ver el ruido.

Distintos tipos de imagen en cada modo

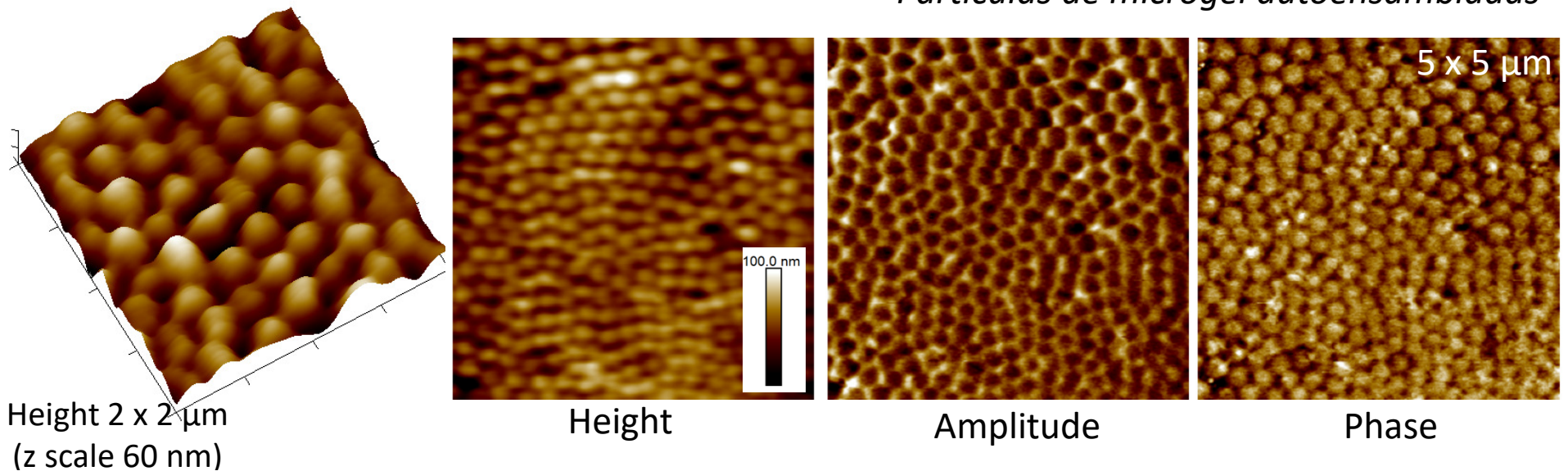
Litografía de polímeros sobre vidrio

Estático

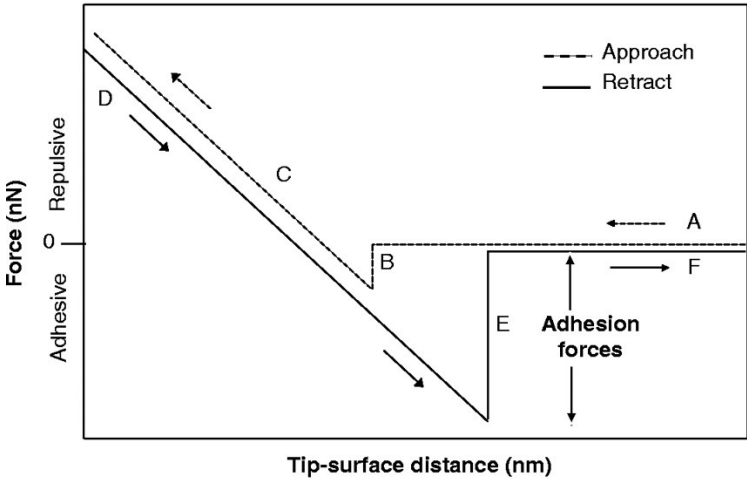
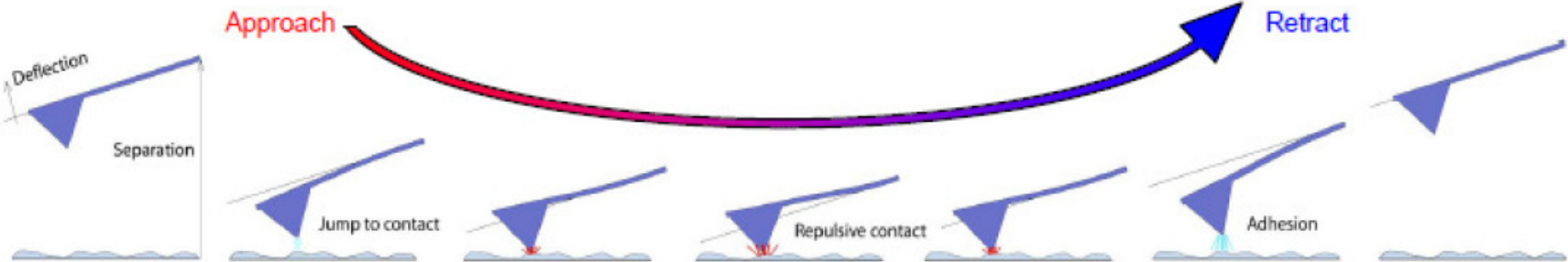


Dinámico

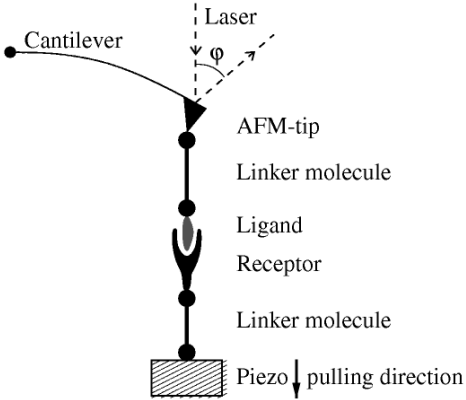
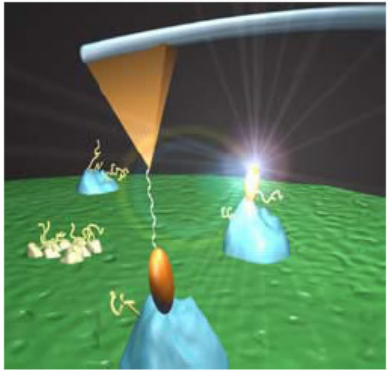
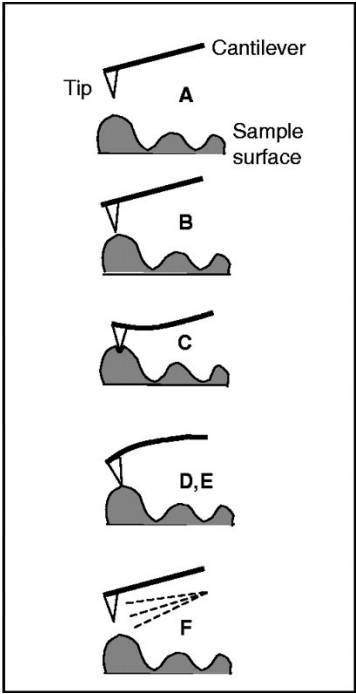
Partículas de microgel autoensambladas



Espectroscopía: curvas de fuerza



Shahin, V. et al. J Cell Sci 2005;118:2881-2889

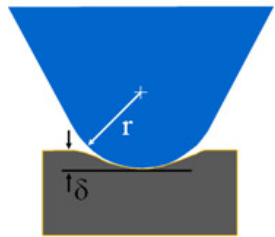


La deflexión puede traducirse a fuerza

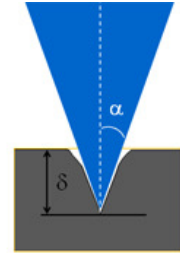
$$F = -k \cdot x$$

constante elástica del cantilever

Propiedades nanomecánicas



E_s : Sample modulus
 ν_s : Poisson's ratio
 r : tip radius of curvature
 α : opening angle

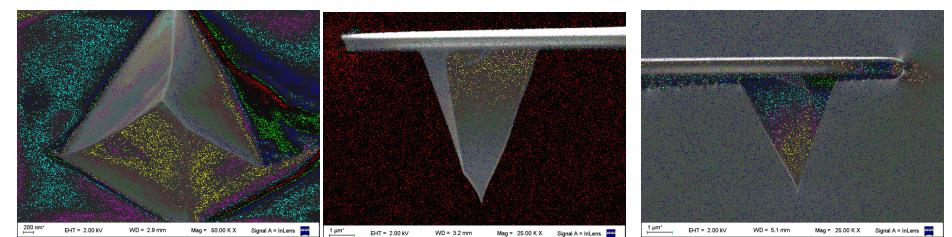
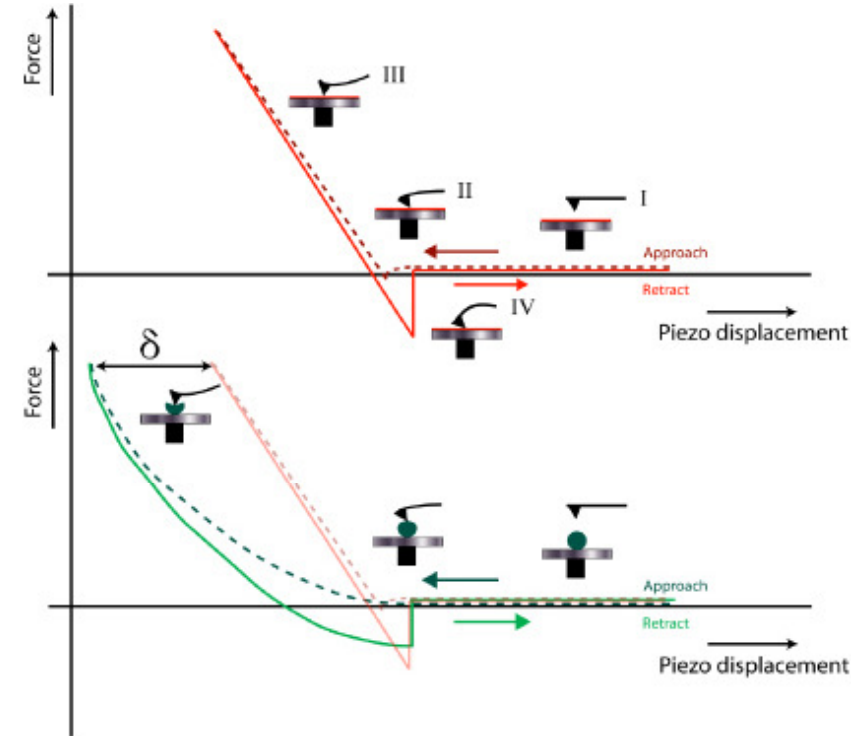
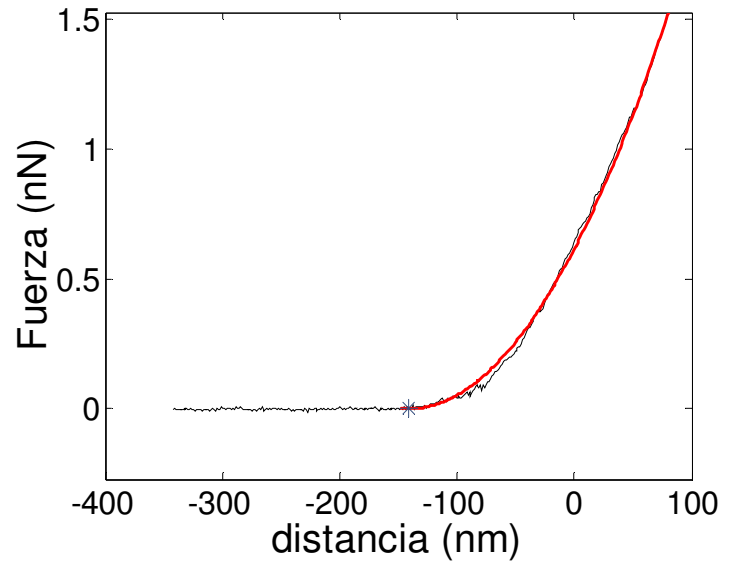


$$F = \frac{4}{3} \cdot \frac{E_s}{1 - \nu_s^2} \cdot \sqrt{r} \cdot \delta^{\frac{3}{2}}$$

Hertz Model

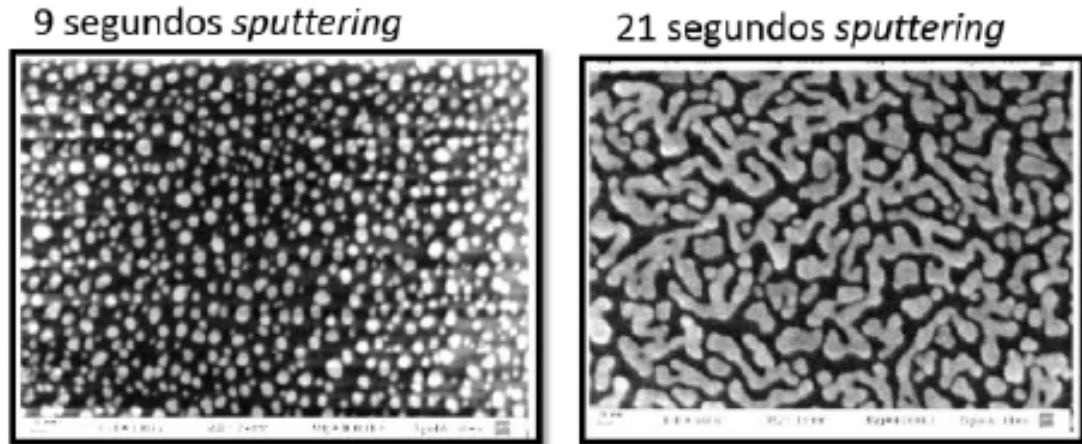
$$F = \frac{2}{\pi} \cdot \frac{E_s}{1 - \nu_s^2} \cdot \tan \alpha \cdot \delta^2$$

Sneddon Model



Nanofabricación

- Sputtering metálico



- Síntesis de nanopartículas de plata

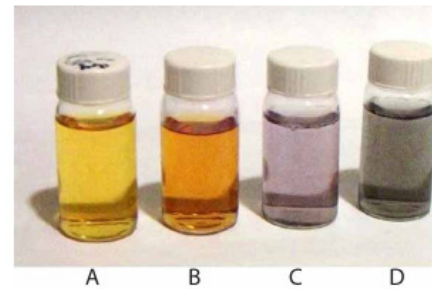


Figure 1. Colloidal silver in various stages of aggregation, (A) clear yellow sol, (B) dark yellow sol, (C) violet sol, and (D) grayish sol, as aggregation proceeds.

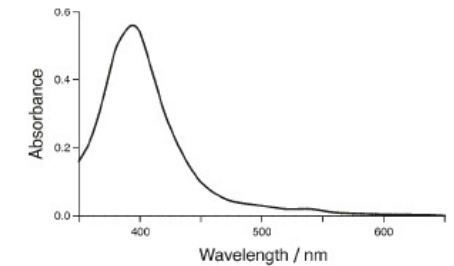
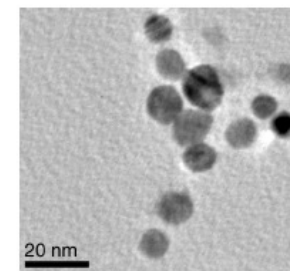


Figure 2. UV-vis absorption spectrum of clear yellow colloidal Ag.

Table 1. Effect on the Stability of Ag Nanoparticles when [NaBH₄] Is Varied

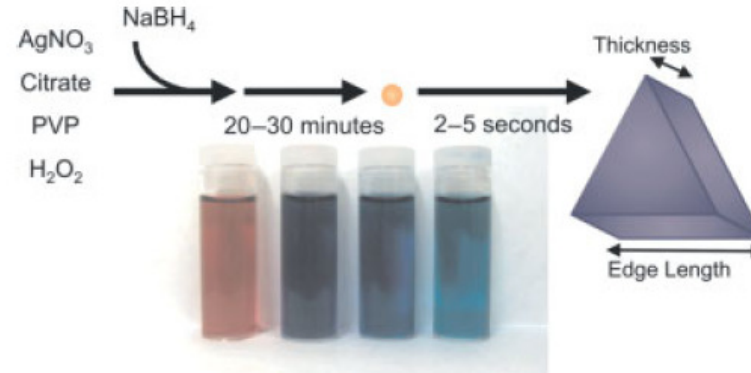
[NaBH ₄]/[AgNO ₃] ^a	Time for Breakdown of Colloid/min
2.0	stable
2.1	~ 30
1.9	~ 20
1.8	~ 5

^a[AgNO₃] is constant at 1.0 mM.



Nanofabricación

- Síntesis de nanoprismas de plata



Scheme 1. The conversion of silver nanoparticles to silver nanoprisms with NaBH₄ and H₂O₂. Inset: Solutions of silver nanoprisms containing various concentrations of NaBH₄ (left to right: 0.30 mM, 0.50 mM, 0.67 mM, and 0.80 mM NaBH₄).

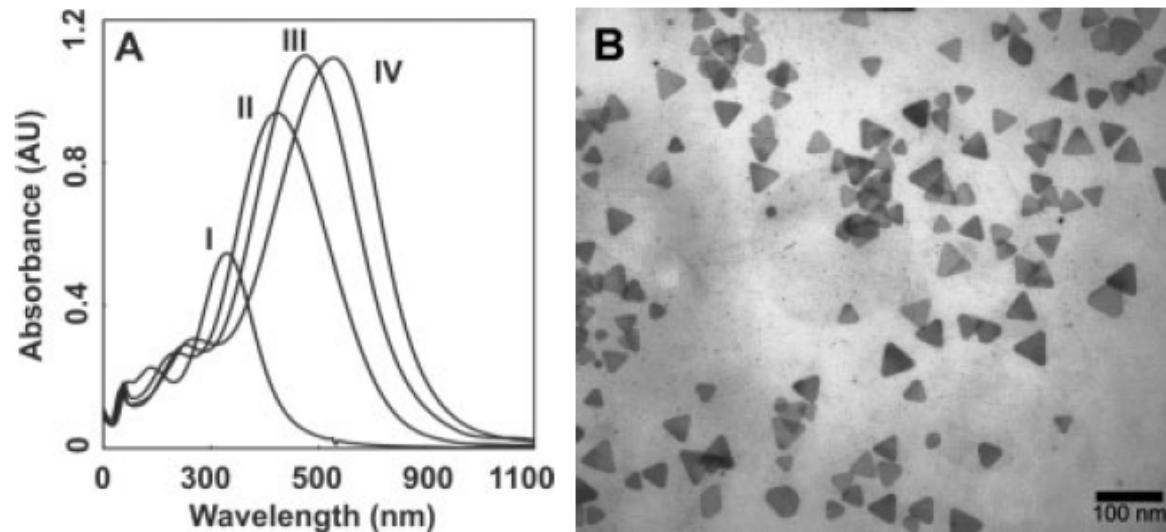


Figure 1. A) UV-vis spectra of nanoprism colloids with various NaBH₄ concentrations ([H₂O₂] = 20 mM). I) 0.30 mM, II) 0.50 mM, III) 0.67 mM, and IV) 0.80 mM. B) TEM image of Ag nanoprisms ([H₂O₂] = 20 mM, [NaBH₄] = 0.80 mM).